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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/891,523	06/27/2001	Ryan N. Rakvic	2207/1123601	3187
23838	7590	12/27/2005	EXAMINER	
KENYON & KENYON 1500 K STREET NW SUITE 700 WASHINGTON, DC 20005			ROJAS, MIDYS	
			ART UNIT	PAPER NUMBER
			2189	

DATE MAILED: 12/27/2005

Please find below and/or attached an Office communication concerning this application or proceeding.



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APPLICATION NO./ CONTROL NO.	FILING DATE	FIRST NAMED INVENTOR / PATENT IN REEXAMINATION	ATTORNEY DOCKET NO.
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09/891523

8/27/01

RAKVIC et al

2207/1123601

EXAMINER

M. J. S. Rojas

ART UNIT PAPER

2185

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DATE MAILED:

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Commissioner for Patents

This office action has been issued in response to Petition to correct inventorship under 37CFR 1.48(a) submitted on 16 February 2005.

In view of the papers filed on 2/16/2005, it has been found that this nonprovisional application, as filed, through error and without deceptive intent, improperly set forth the inventorship, and accordingly, this application has been corrected in compliance with 37 CFR 1.48(a). The inventorship of this application has been changed by adding the previously unnamed person as inventor of this application: Deepak Limaye.

The application will be forwarded to the Office of Initial Patent Examination (OIPE) for issuance of a corrected filing receipt, and correction of Office records to reflect the inventorship as corrected.

Mano Padmanabhan
Mano Padmanabhan
AU2188
12/20/05

MANO PADMANABHAN
SUPERVISORY PATENT EXAMINER